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Application/Control No.	Applicant(s)/Patent under Reexamination	
09/503,608	ATTWOOD ET AL.	
Examiner	Art Unit	
Ellen C. Tran	2134	

SEARCHED			
Class	Subclass	Date	Examiner
726	22	10/10/2006	ECT
726	23	10/10/2006	ECT
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
USPTO, USPG, EPO, JPO, OCR, DERWENT, IBM TECH DES	10/10/2006	ECT
NPL - IEEE XPLORE	10/10/2006	ECT
All claims have been reviewed for possible 101 rejections	10/10/2006	ECT
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Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
09/503,608	ATTWOOD ET AL.
Examiner	Art Unit
Elles C. Tres	2124

SEARCHED			
Class	Subclass	Date	Examiner
726	22	4/26/2006	ECT

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
USPTO, USPG, EPO, JPO, DERWENT, IBM TECH DES	4/26/2006	ECT
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Application No.	Applicant(s)
09/503,608	ATTWOOD ET AL.
Examiner	Art Unit
Ellen C Tran	2134

SEARCHED					
Class	Subclass	Date	Examiner		
713	201	3/30/2005	ECT		
713	190	3/30/2005	ECT		

INTERFERENCE SEARCHED				
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USPTO, USPG, EPO, JPO, DERWENT, IBM TECH DES	3/30/2005	ECT
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SEARCHED SEARCH NOTES (INCLUDING SEARCH STRATEGY) Class Sub. Date Exmr. Date Exmr. 200-210 395 SEE ATTACHED 607. 10 NO 245 "SE BACH HISTORY 113=501 ECT 370 שינ נפן סן 7 APPLY ECT 50-210 USPTO 704 USPG 710 52-57 EPO 711 100 260 7 APR'S DERWENT ECT 3:70 229 429 1BM TECH PS 280 25 709 332 239 713 200 201 714 4 18 INTERFERENCE SEARCHED Class Sub. Exmr. Date